



Device Test Report

Device Test System Revision : 3.1.1.4 Build: 2020-9-2 Test ID:653046495



Vendor : Banner Engineering Corporation

Device Name : Q76E IO-Link

Vendor ID : 0x01C3

Device ID : 0x071301

IO-Link Version : 1.1

Product ID : Q76E

ISDU supported : False

SIO mode supported : True

Process Data Input Bits : 8

Process Data Output Bits : 1

Min Cycle Time : 2300 μ s

Bitrate : COM2

Implemented Access Locks :

parameter="False" datastorage="False" localParameterization="False" localUserInterface="False"

IODD : Banner_Engineering-Q76E-KP-ZLVC-Q5-20200801-IODD1.1.xml

Checker : IODD-Checker V1.1.4

CRC : 705090584

Firmware Revision : not known

Hardware Revision : not known

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Test result : All test were passed with positiv result in complete operation

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Test operated by :

Company : Banner EngineeringName : Paul FabianSignature : [Signature]

Testreport : Test Configuration

Test variable for 8 Bit index access :

Index : 0

Length: 0

Data (hex) :

Test variable for 16 Bit index access :

Index : 0

Length: 0

Data (hex) :

Test variable for 8 Bit index extended length :

Index : 0

Length: 0

Data (hex) :

Implemented system commands :

0 1

M-sequence Capability (hex) :

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===== Config Messages from Testcases =====

The testcase is skipped because the device is not capable to generate events during the test
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The device is not able to stimulate 2 different events of type error in parallel. Test case is ignored
The testcase is skipped because the device is not capable to generate events during the test

Testreport Overview (1)

TC_Device_Identification	ok
Data Layer Tests V1.0.3.52	
SDCI_TC_0034 TCD_DLPC_STUP_CYCTIME	ok
SDCI_TC_0035 TCD_DLPC_STUP_STUOPER1	ok
SDCI_TC_0036 TCD_DLPC_STUP_STUOPER2	ok
SDCI_TC_0037 TCD_DLPC_OPER_OPERSTUP1	ok
SDCI_TC_0038 TCD_DLPC_STAR_OPERSTAR2	ok
SDCI_TC_0039 TCD_DLPC_PREO_READDPP1	ok
SDCI_TC_0040 TCD_DLPC_PREO_WRITEDPP1	ok
SDCI_TC_0041 TCD_DLPC_PROP_SHORT_FRAME	ok
SDCI_TC_0043 TCD_DLPC_PROP_SIMRESET	ok
SDCI_TC_0044 TCD_DLPC_PROP_FRAMEFAULT	ok
SDCI_TC_0045 TCD_DLPC_OPER_READ	ok
SDCI_TC_0046 TCD_DLPC_OPER_WRITE	ok
SDCI_TC_0047 TCD_DLPC_OPER_NEGWRITE	ok
SDCI_TC_0049 TCD_DLPC_OPER_SIMRESET	ok
SDCI_TC_0306 TCD_DLPC_CHCK_OVERRIDOK	ok
ISDU Tests V1.0.3.52	
Event Tests V1.0.3.52	
SDCI_TC_0069 TCD_DLIC_EVNT_OPERSINGLEEVENT	ok
SDCI_TC_0070 TCD_DLIC_EVNT_PROPSINGLEEVENT	ok
SDCI_TC_0071 TCD_DLIC_EVNT_OPEREVENTCLEAR	ok
SDCI_TC_0072 TCD_DLIC_EVNT_OPERCOMMINTERRUPT	ok
SDCI_TC_0073 TCD_DLIC_EVNT_OPERPOWERINTERRUPT	ok
SDCI_TC_0074 TCD_DLIC_EVNT_OPERAPPEARDISAPPEAR	ok
SDCI_TC_0075 TCD_DLIC_EVNT_OPERMULTEVENT	ok
SDCI_TC_0076 TCD_DLIC_EVNT_OPERSHORTEVENT	ok
Data Storage Tests V1.0.3.52	
Legacy Master Tests V1.0.3.52	
SDCI_TC_0085 TCD_DLIC_COMP_STARTUP	ok
SDCI_TC_0086 TCD_DLIC_COMP_TYPE1INTERLEAVE	ok
SDCI_TC_0087 TCD_DLIC_COMP_PDINVALIDEVENT	ok
Direct Parameter Page 1 Tests V1.0.3.52	
SDCI_TC_0089 TCD_DLPC_STDP_MASTERCYCLETIME	ok
SDCI_TC_0090 TCD_DLPC_STDP_MINCYCLETIME	ok
SDCI_TC_0091 TCD_DLPC_STDP_FSEQCAPABILITY	ok
SDCI_TC_0092 TCD_DLPC_STDP_REVISIONID	ok
SDCI_TC_0093 TCD_DLPC_STDP_PDIN	ok
SDCI_TC_0094 TCD_DLPC_STDP_PDOUT	ok
SDCI_TC_0095 TCD_DLPC_STDP_VENDORID	ok
SDCI_TC_0096 TCD_DLPC_STDP_DEVICEID	ok
SDCI_TC_0097 TCD_DLPC_STDP_FUNCTIONID	ok

Testreport Overview (2)

SDCI_TC_0100 TCD_DLPC_STDP_READRESPAR	ok
SDCI_TC_0101 TCD_DLPC_STDP_WRITERESPAR	ok
Predefined Device Parameter Tests V1.0.3.52	
Block Parameter Tests V1.0.3.52	
IODD based Tests V1.0.3.52	
SDCI_TC_0149 TCD_IODD_PARV_IDENT	ok
SDCI_TC_0150 TCD_IODD_PARV_COMPROFILE	ok
SDCI_TC_0151 TCD_IODD_PARV_READVERIFY	ok
SDCI_TC_0152 TCD_IODD_PARV_WRITEVERIFY	ok
SDCI_TC_0155 TCD_IODD_PARV_FACTORYSETTINGS	ok
SDCI_TC_0156 TCD_IODD_PARV_ACCESSLOCK	ok
SDCI_TC_0157 TCD_IODD_PARV_INDEXCONSISTENT	ok
support of Physical Layer Tests V1.0.3.52	
SDCI_TC_0304 TCD_PHYL_INTF_UARTTRANSDelay	ok
SDCI_TC_0305 TCD_PHYL_INTF_RESPONSETIME	ok

Test Report Statistics:

Number of test cases overall : 47
Number of test cases ok : 47
Number of test cases failed : 0
Number of test cases skipped : 0
Test Operation : complete